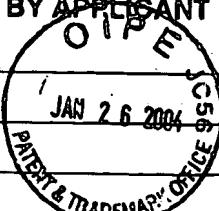


Sheet 1 of 3 sheets

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. AMAT/2966.C1/DSM /BCVD/JW	Serial No. 10/684,079
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Applicant Bencher, et al.	Confirmation No. Unknown
(Use several sheets if necessary)				Filing Date October 9, 2003	Group Unknown
	Examiner Unknown				

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V.Y.	A1	6,528,426	03/04/2003	Olsen, et al.	438	689	10/15/1999
A	A2	6,514,667	02/04/2003	Angelopoulos, et al.	430	271.1	08/17/2001
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	A12	5,926,740	07/20/1999	Forbes, et al.	438	763	10/27/1997
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*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
V.Y.	B1	0 725 440	08/07/1996	EP	H01L	23/532	<input type="checkbox"/>	<input checked="" type="checkbox"/>
V.Y.	B2	0 613 178	02/22/1994	EP	H01L	21/90	<input type="checkbox"/>	<input checked="" type="checkbox"/>
V.Y.	B3	99/33102	07/01/1998	WO	H01L	21/767	<input type="checkbox"/>	<input checked="" type="checkbox"/>

OTHER ART

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V.Y.	C1	Written Opinion from PCT/US99/22424, Dated April 5, 2001.
V.Y.	C2	PCT International Search Report for PCT/US99/22425, Dated February 2, 2000.

Examiner *J. Yostkov* Date Considered *04/29/05*

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Bencher, et al.	Confirmation No. Unknown
(Use several sheets if necessary)		JAN 26 2004 PATENT & TRADEMARK OFFICE	Filing Date October 9, 2003
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A	A18	5,789,316	08/04/1998	Lu	438	638	03/10/1997
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N.Y.	C4	Dijkstra, et al., "Optimization of Anti-Reflection Layers for Deep UV Lithography", Proceedings of SPIE Optical Laser Microlithography, Bellingham, SPIE, Vol. 1927, pages 275-286.
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V.Y.	C6	PCT International Search Report for PCT/US99/22317, Dated March 21, 2000.

Examiner *V.Y. Bencher* Date Considered *04/29/05*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/2966.C1/DSM /BCVD/JW	Sheet 3 of 3 sheets Serial No. 10/684,079
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Bencher, et al.	Confirmation No. Unknown
(Use several sheets if necessary)		JAN 26 2004 PATENT AND TRADEMARK OFFICE RECEIVED	Filing Date October 9, 2003
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Examiner V. The Year

Date Considered 04/29/05

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